

Oscilloscope

Osc. Active

Channel 1

Manual

Save

Button is clicked to activate oscilloscope or show graph at memory

To catch the last signal automatically

Synchronous

Channel 1

Up

1. Channel

Probe X1

Top Value : 2,98 V

Low Value : -0,02 V

Point :

Frequen. : 1,6 KHz

Position of probe's switch: X 1 or X 10

Ch.1 Input signal values

2. Channel

Probe X1

Top Value : 0,00 V

Low Value : 0,00 V

Point :

Frequen. :

ATTENTION: Chassis to connect to the point must be isolated or grounded. ADVICE: Use Probe is 10X position.

Analog Output (Channel 2)

Active

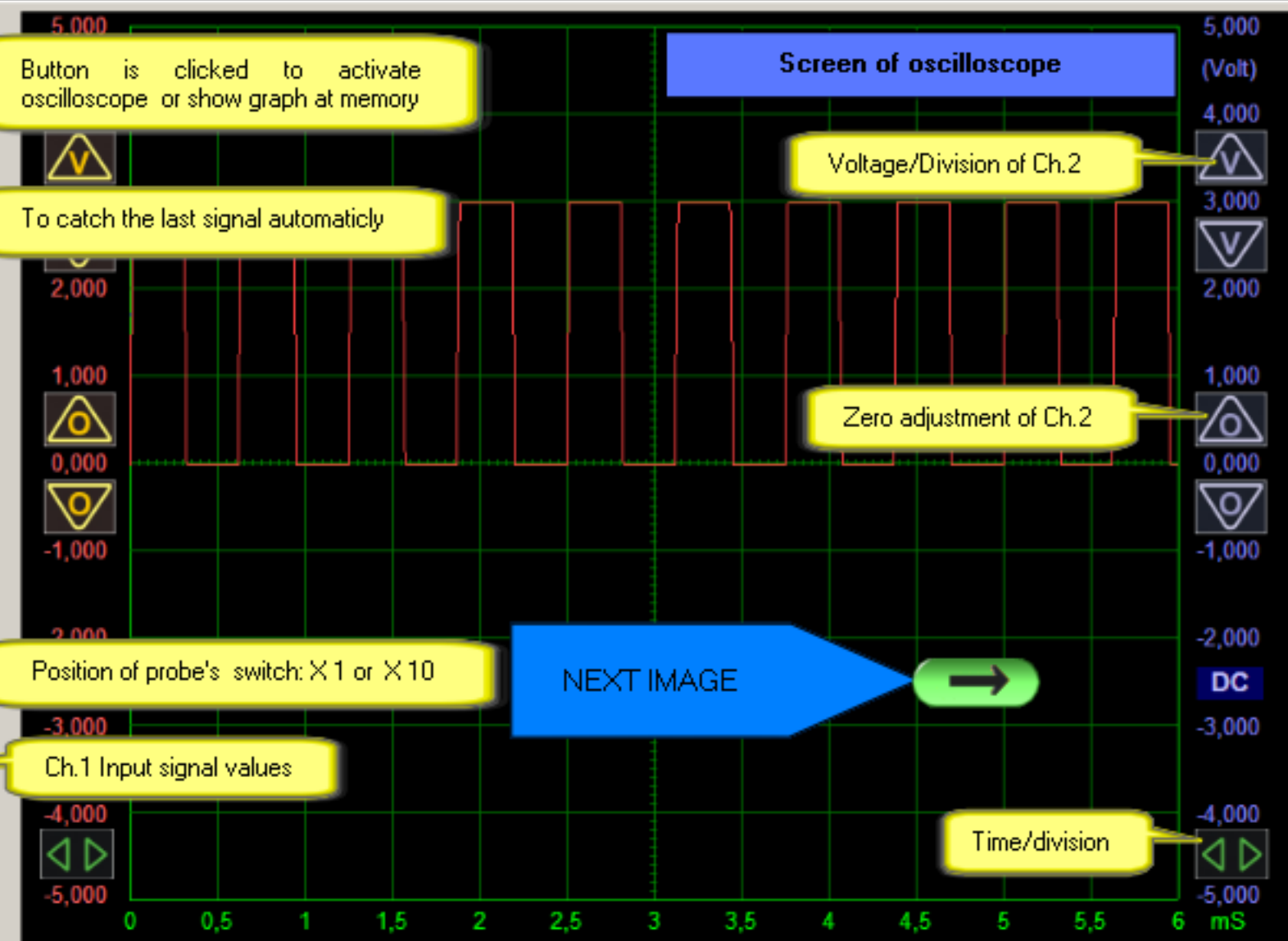
Ch.2 activates output signal

Signal

DAC

Frequency : 1600

Voltage mV: 3000



5,000 (Volt)

4,000

3,000

2,000

1,000

0,000

-1,000

-2,000

-3,000

-4,000

-5,000

DC

0

0,5

1

1,5

2

2,5

3

3,5

4

4,5

5

5,5

6

mS

Test:

Channel 1 - 2

Automatic

1 V
2 V
5 V
10 V

Very Low Frk.
Low 2 Frk.
Lov 1 Frk.
Test Frk.
H Frk (5-10V)

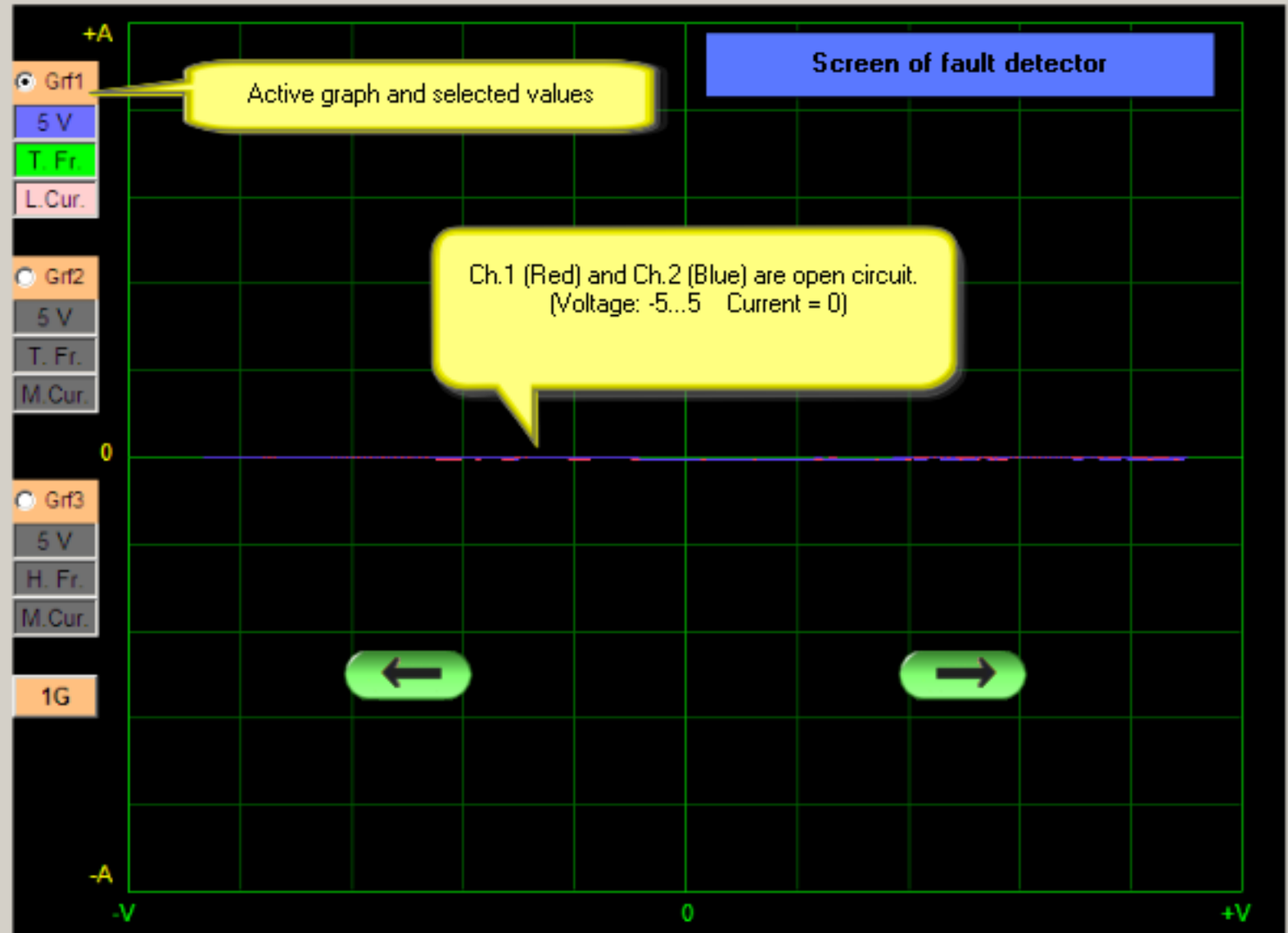
L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capasite Test
 T.T.T. FET IGBT

Memory Save - Test

Recording

Tolerance (%)



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

Reference: Ch1 —

Open Circuit

Test: Ch2 —

Open Circuit

Click to display fault detector screen

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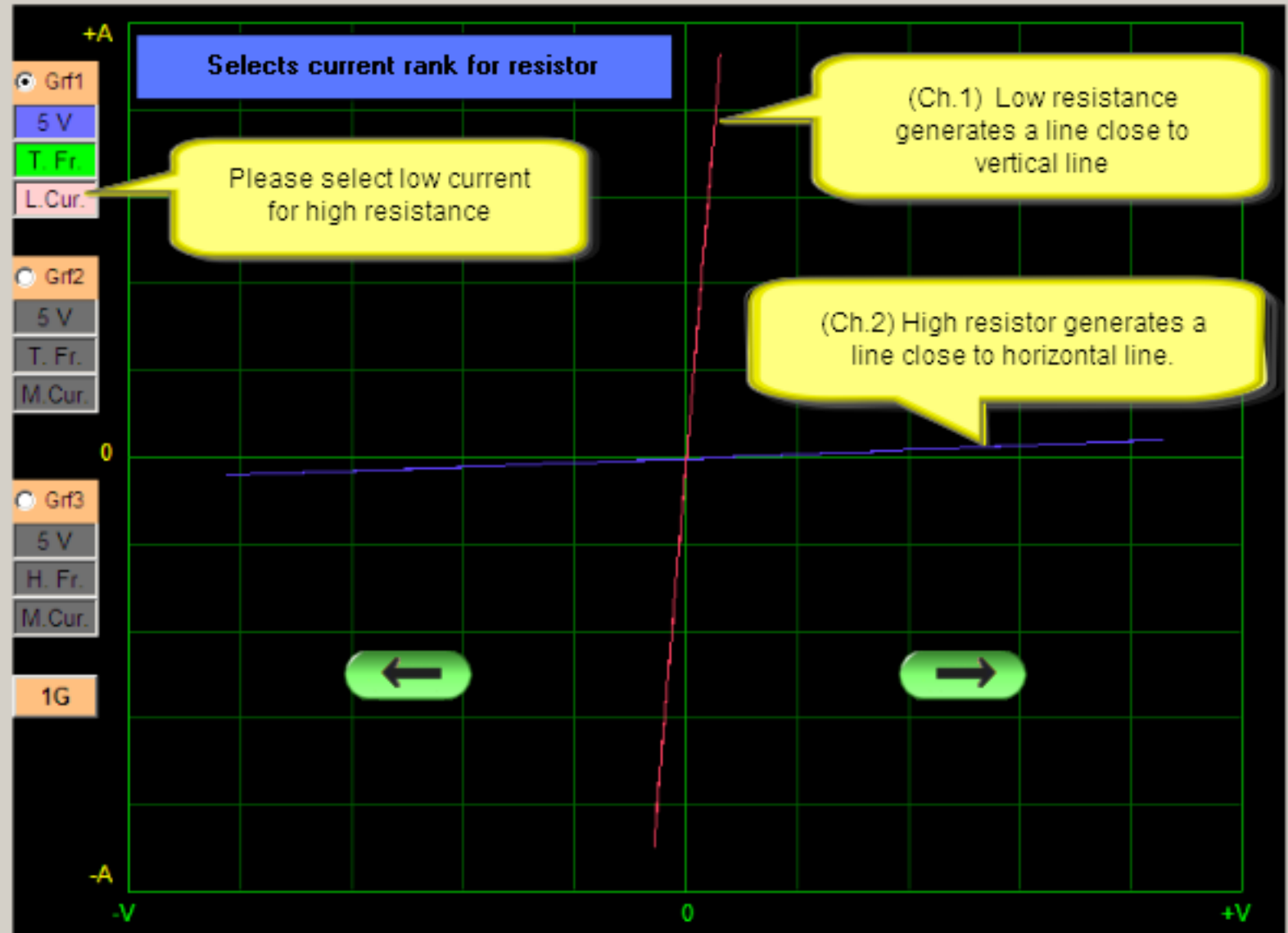
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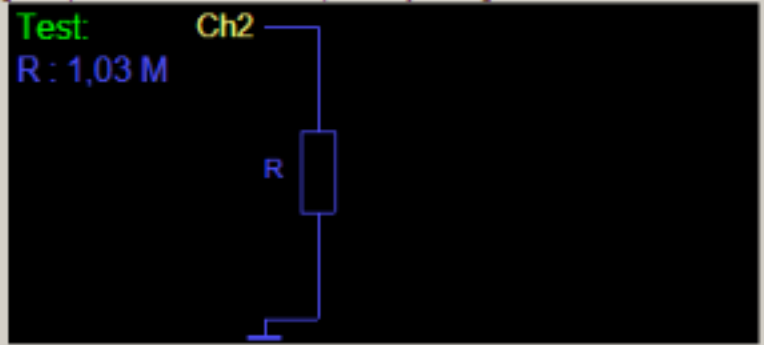
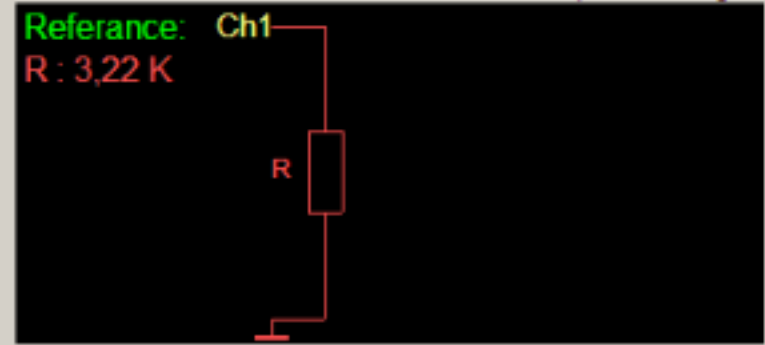
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Recording

Tolerance (%) **3**



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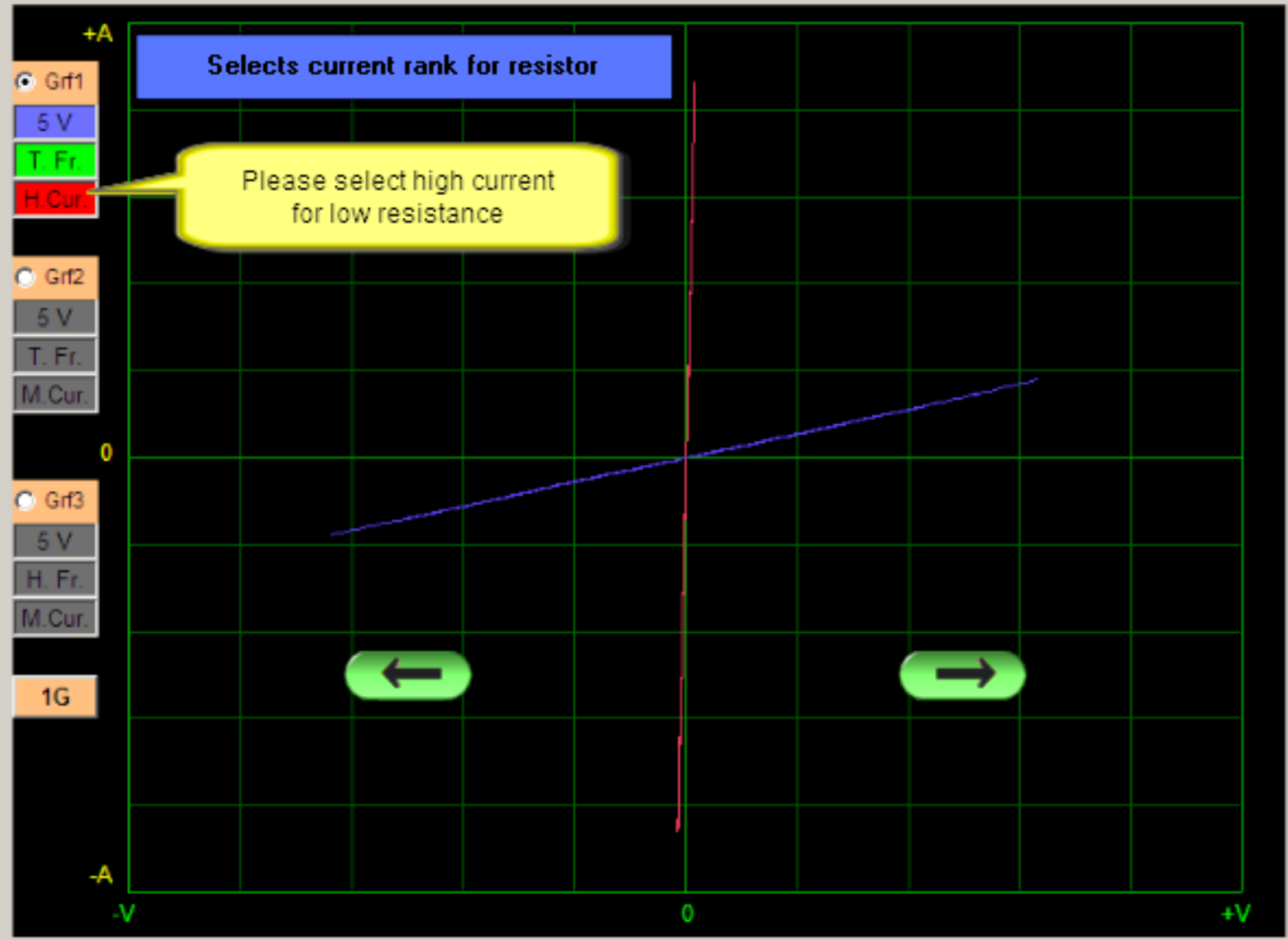
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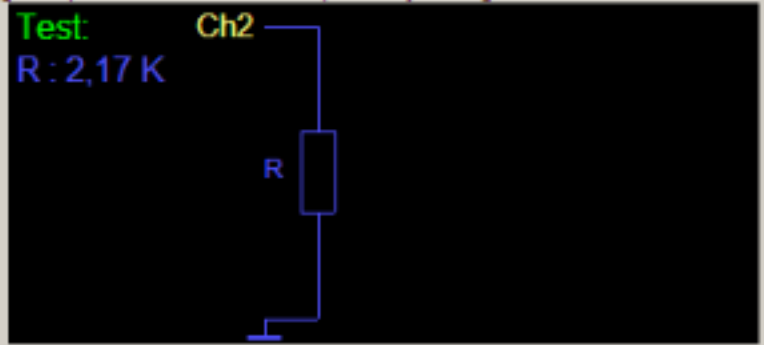
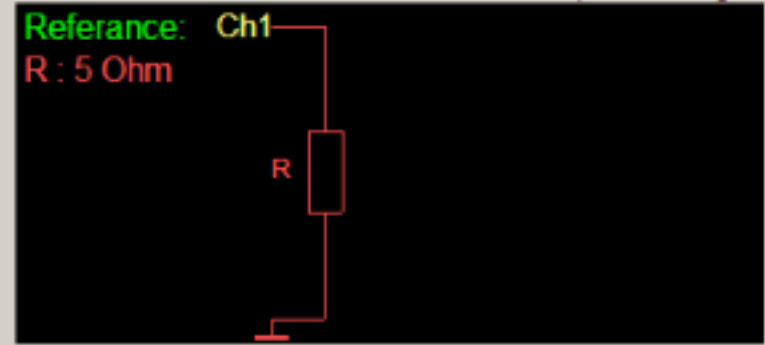
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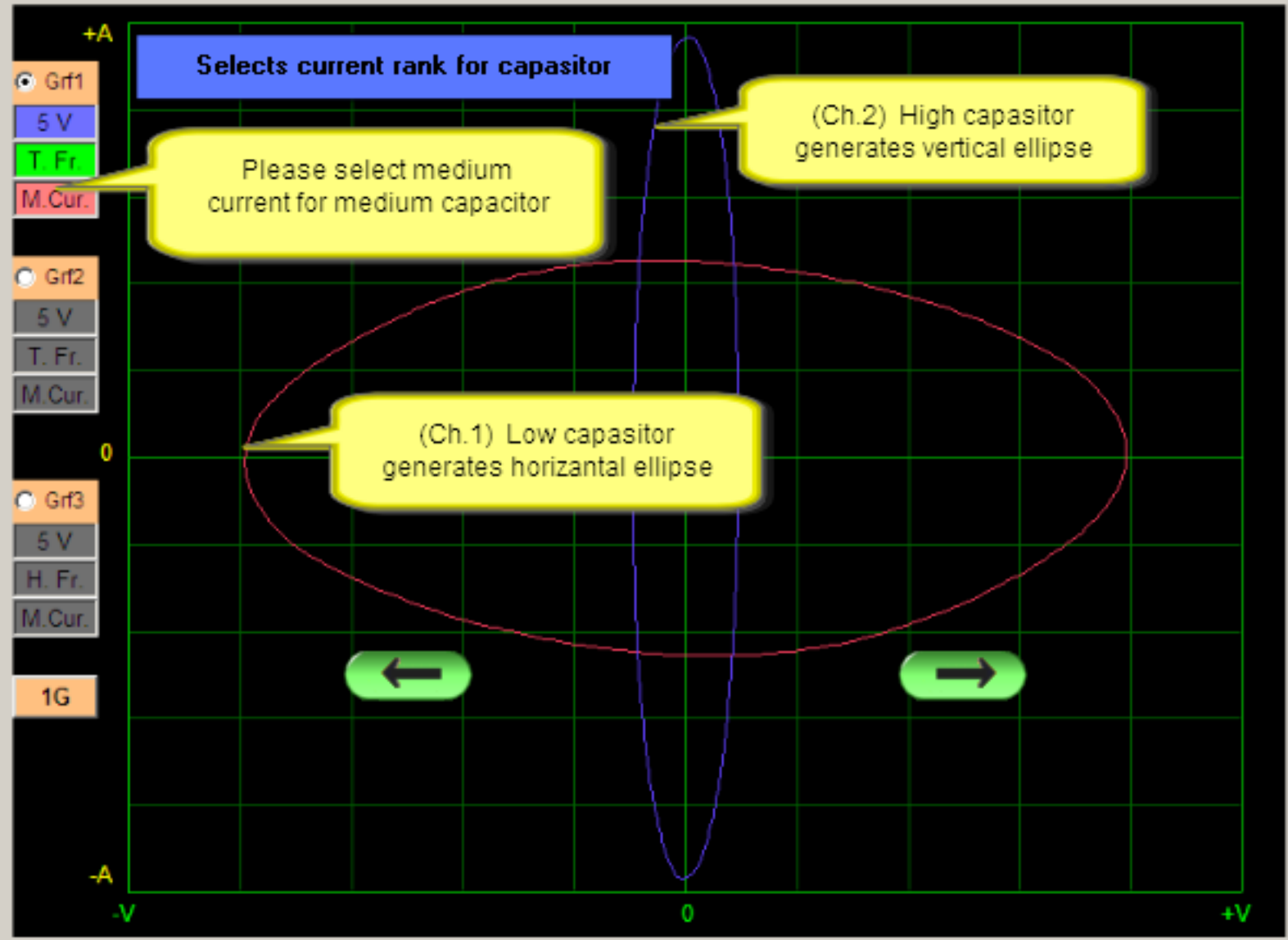
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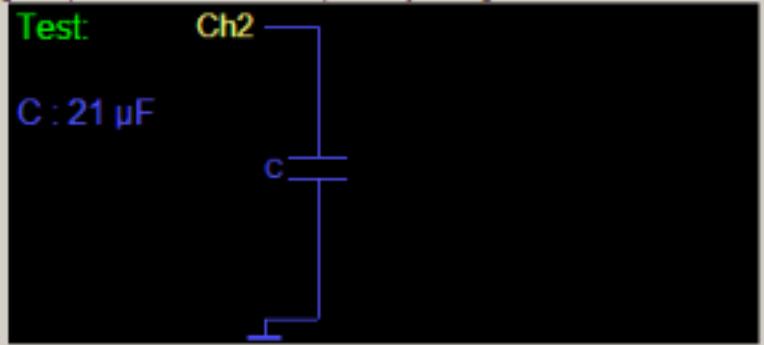
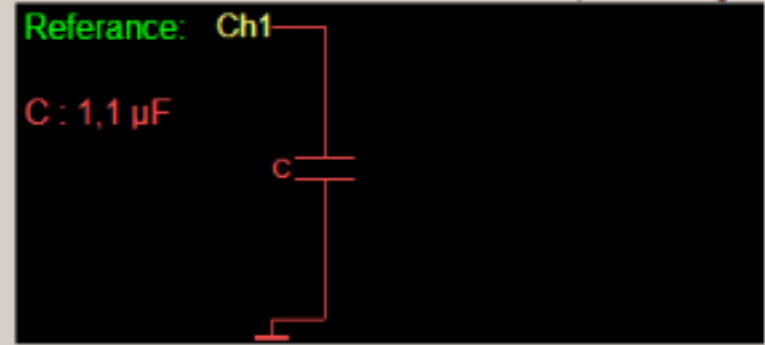
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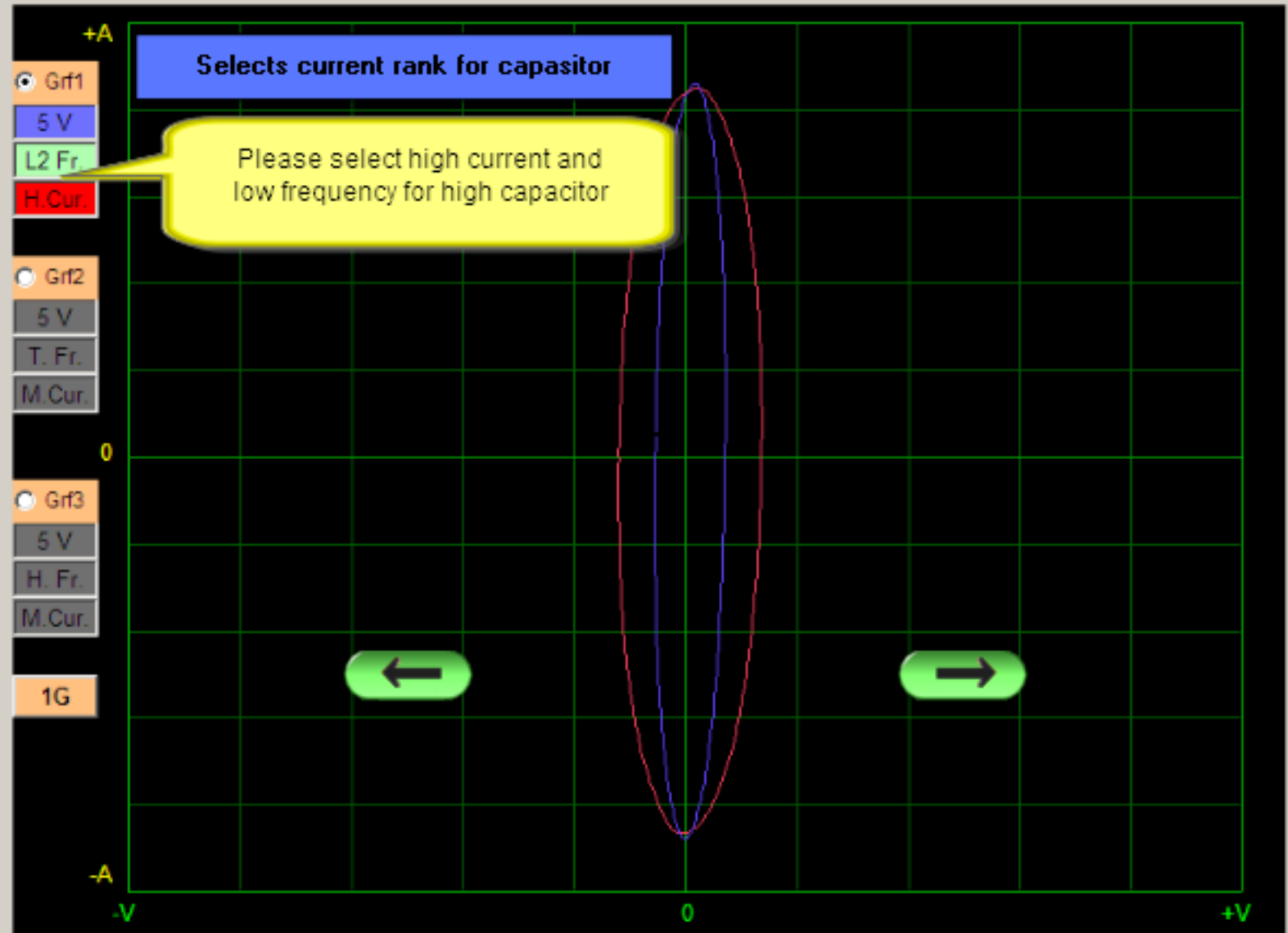
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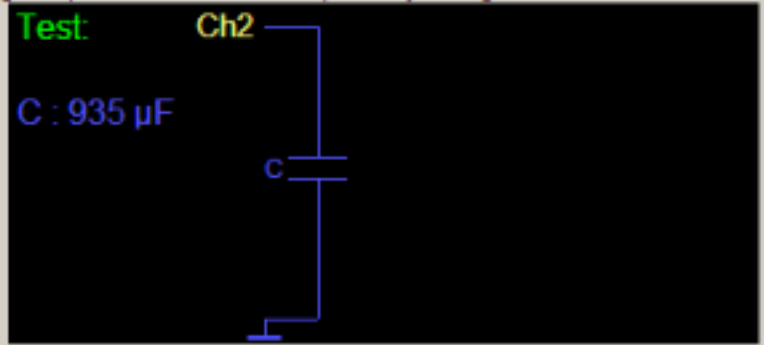
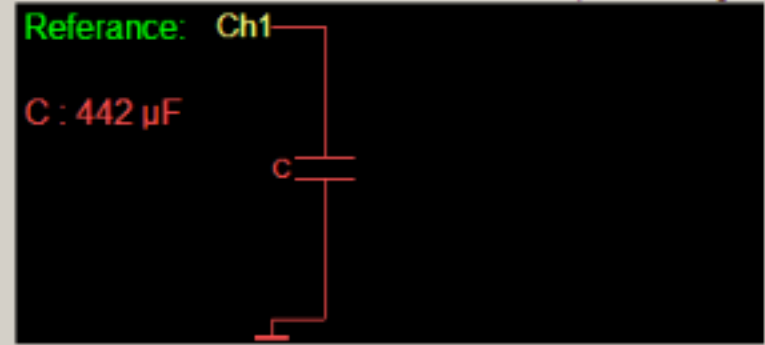
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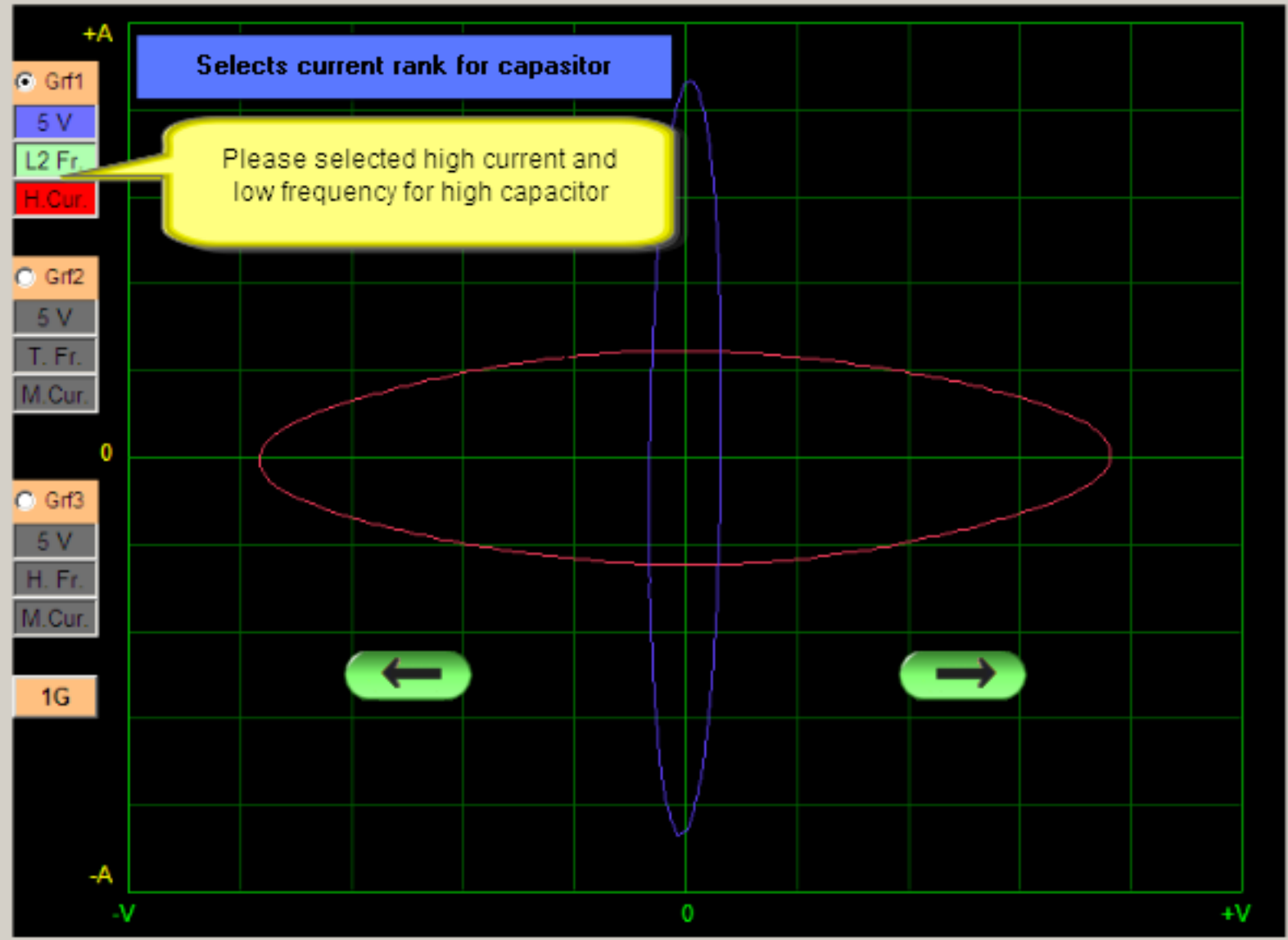
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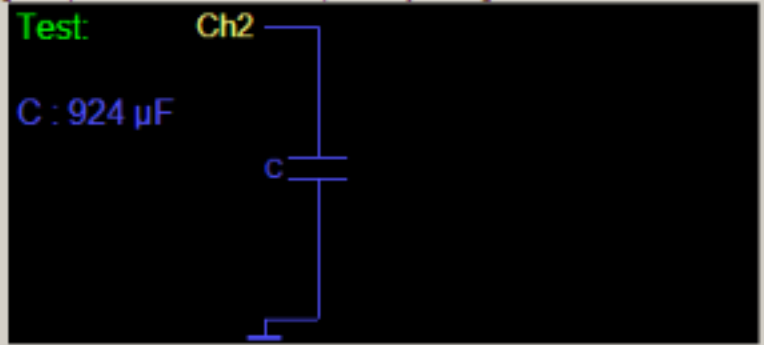
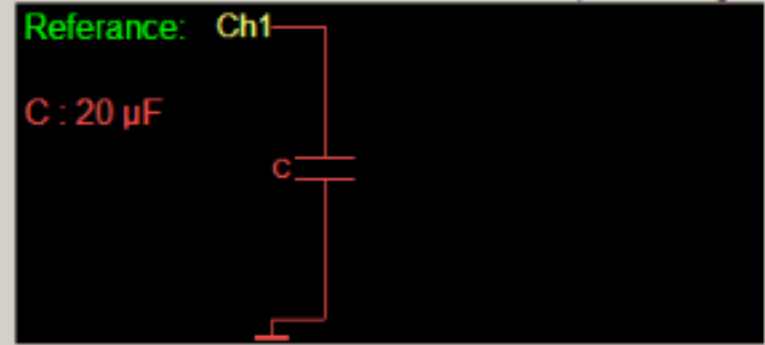
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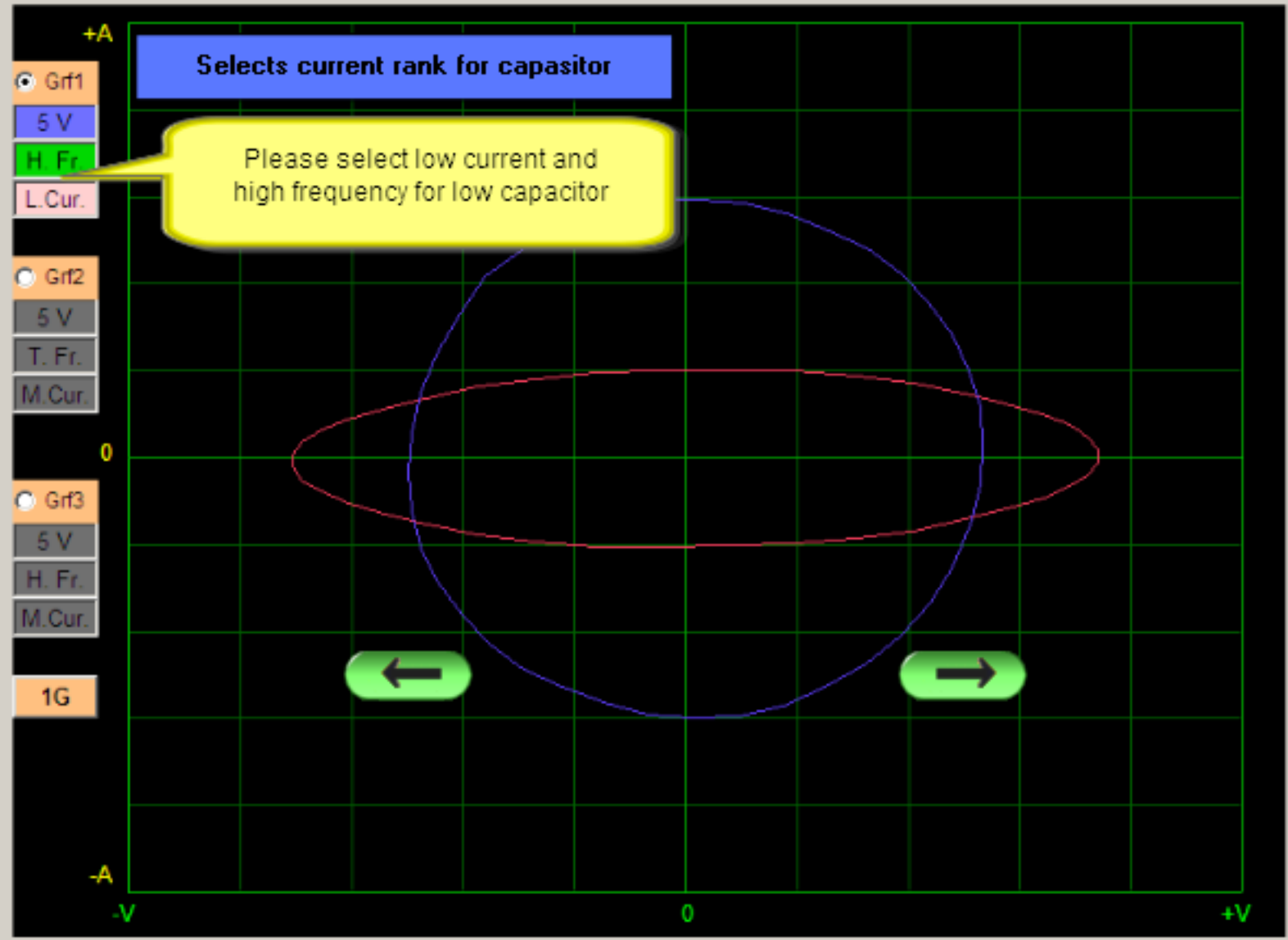
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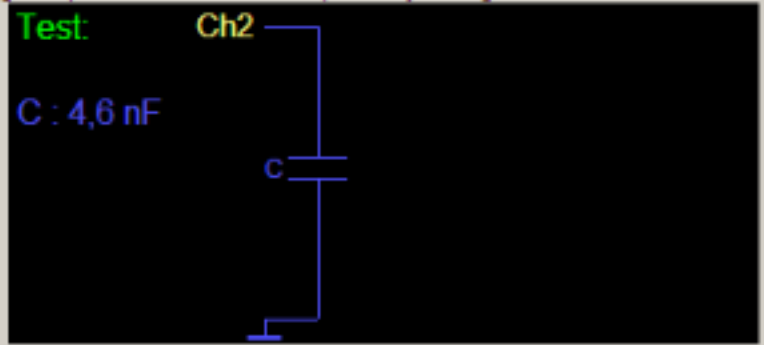
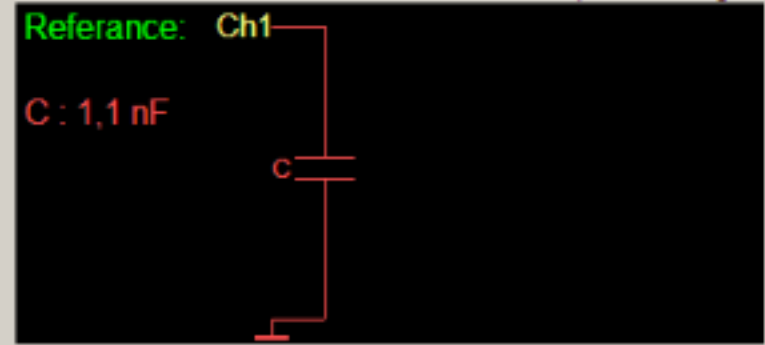
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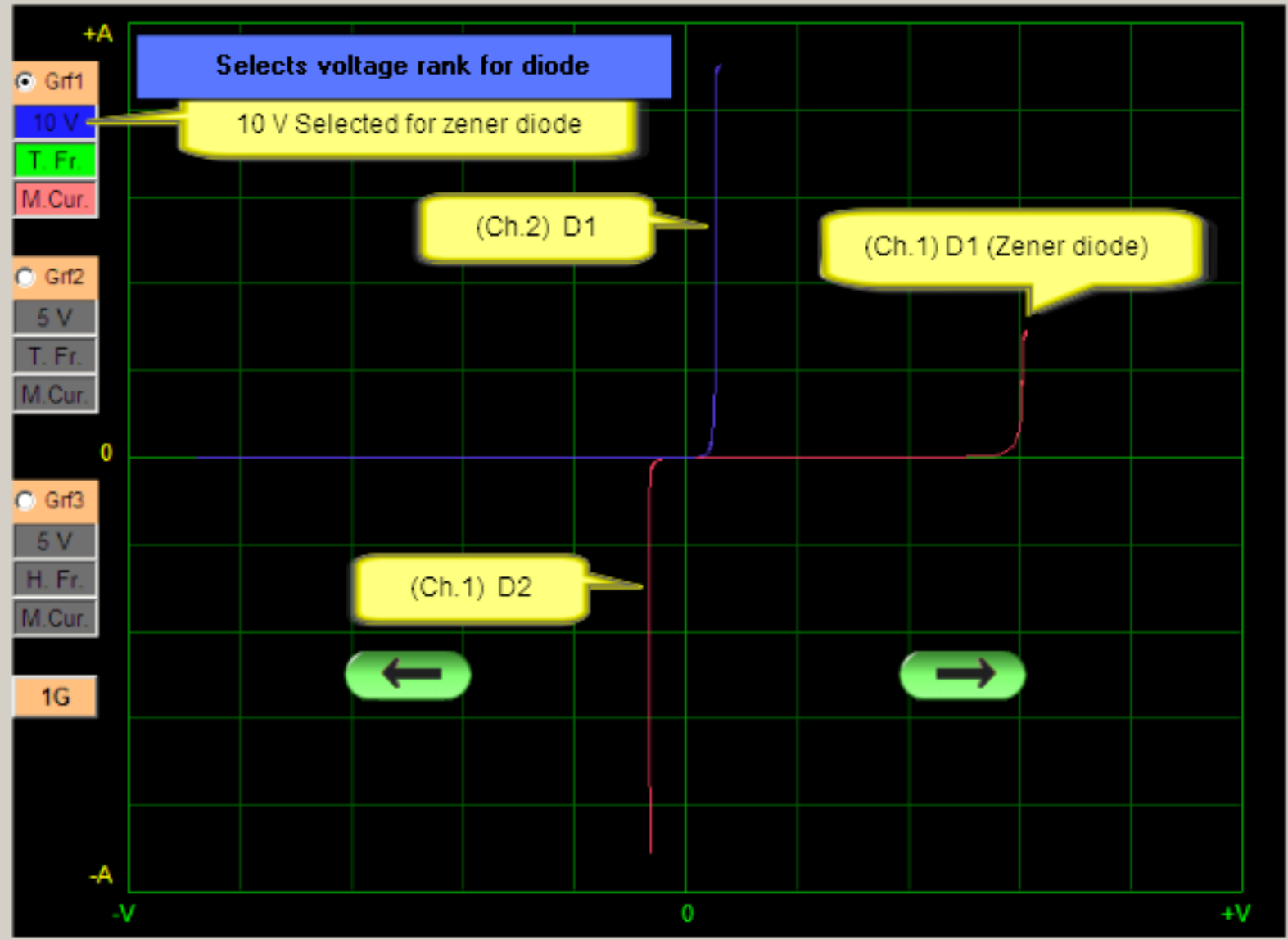
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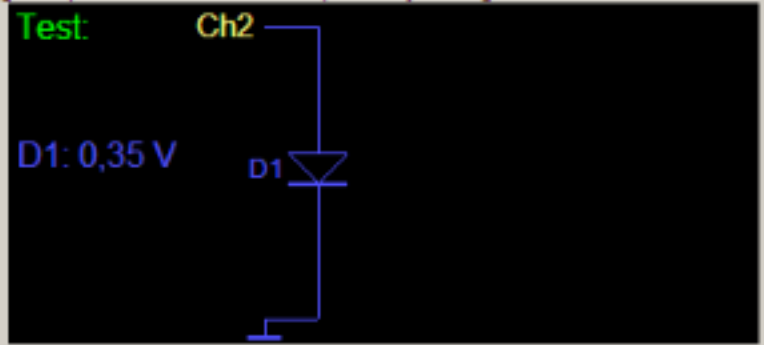
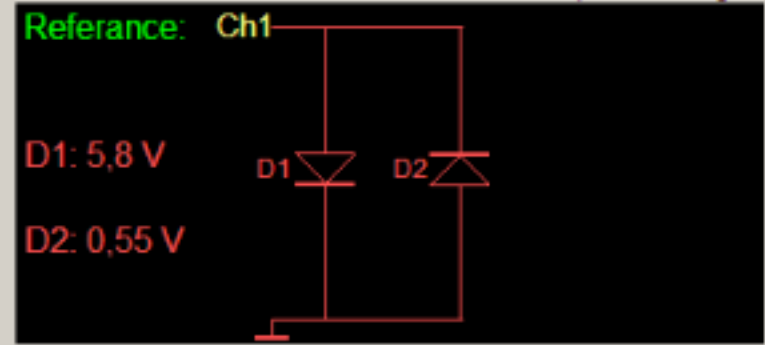
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OSCILLOSCOPE - ANALOG OUTPUT

FAULT DETECTOR - VI TESTER

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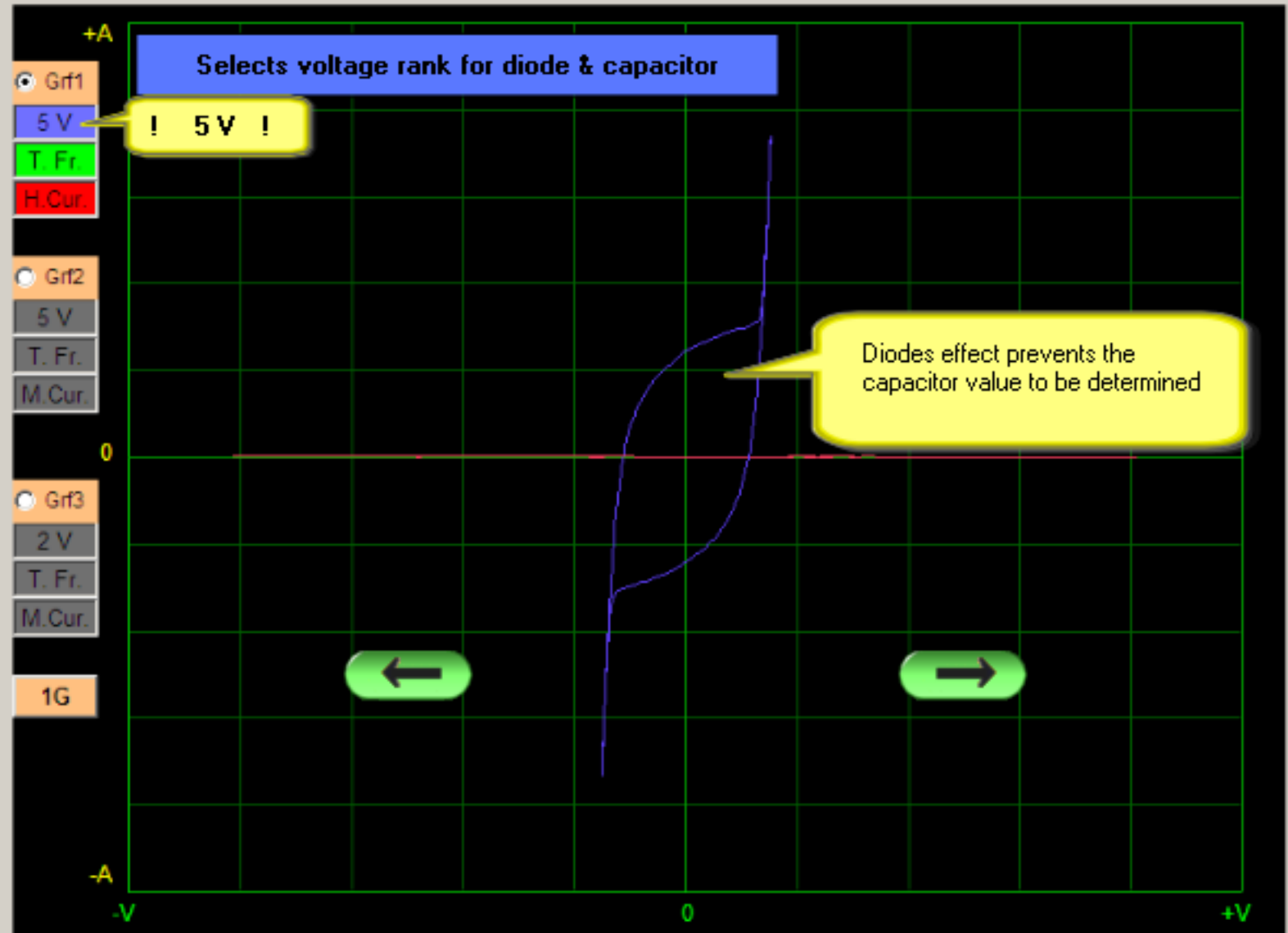
Capasite Test

T.T.T. FET IGBT

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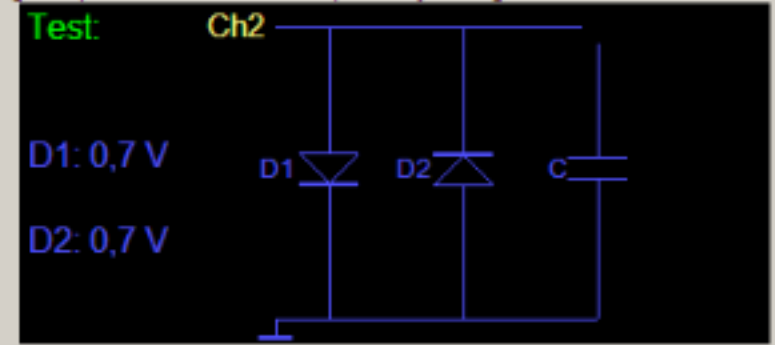
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Reference: Ch1 —

Open Circuit



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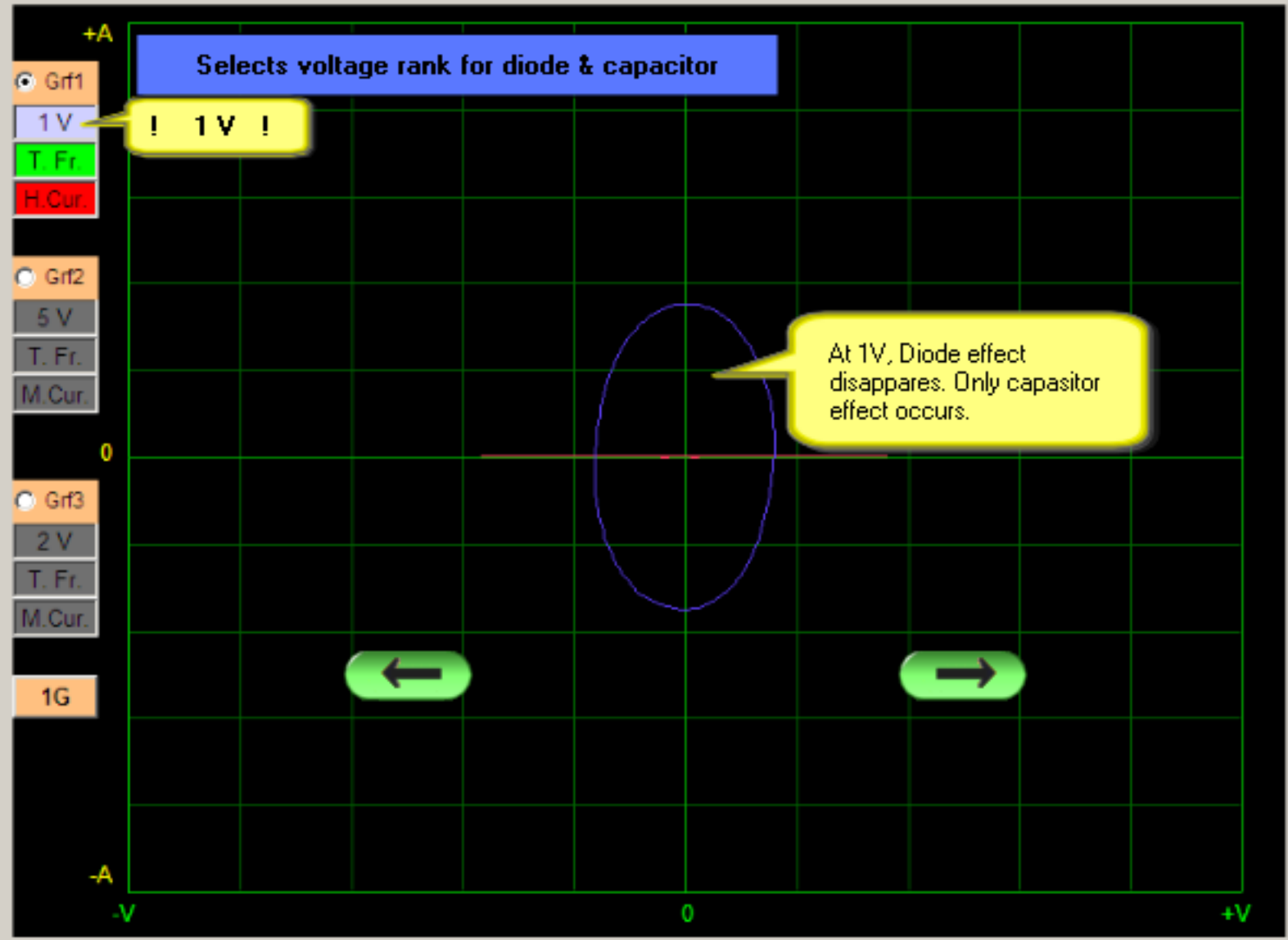
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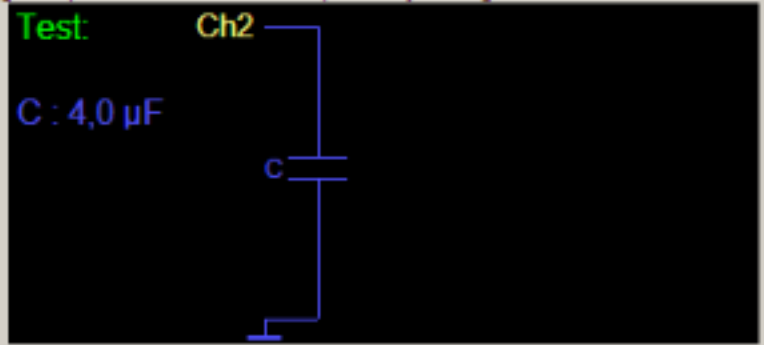
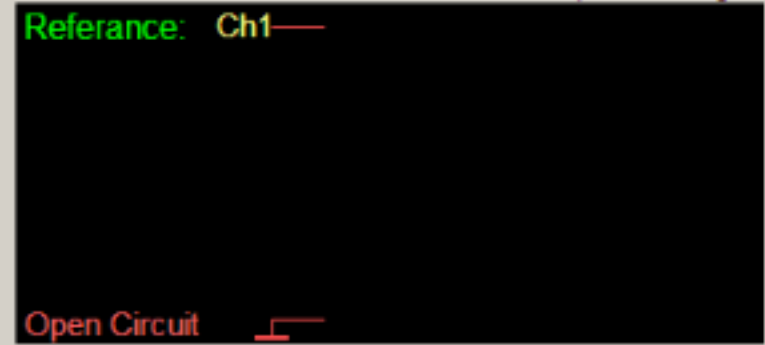
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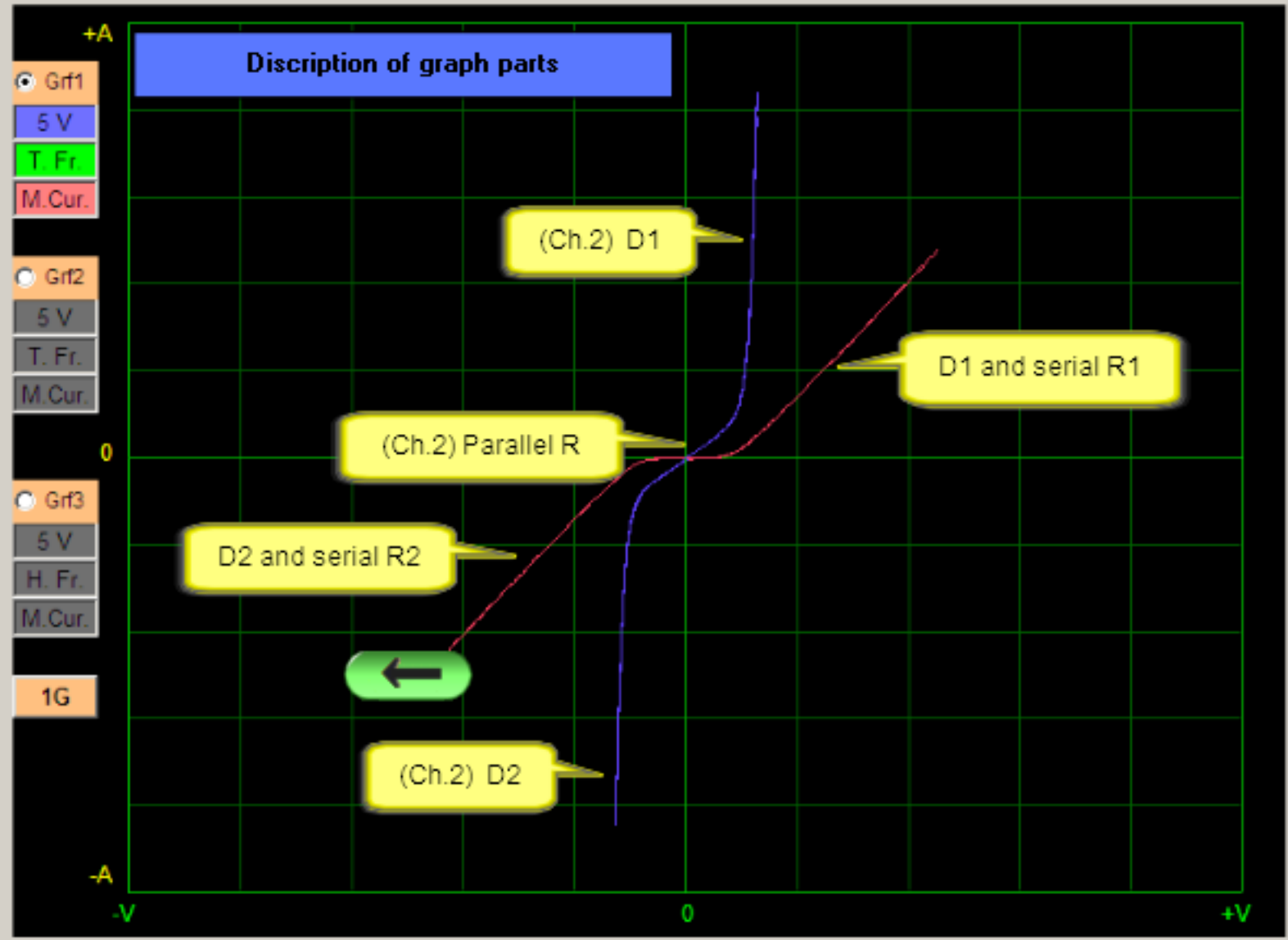
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